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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10051375	FILING DATE 01-17-2002	CLASS 372	SUBCLASS -	GAU 2821	EXAMINER -
**APPLICANTS: Eom Tae Suh Ho Choi Tae					
**CONTINUING DATA VERIFIED:					
** FOREIGN APPLICATIONS VERIFIED: REPUBLIC OF KOREA 2001 48463 08/11/2001 REPUBLIC OF KOREA 2001-52030 08/28/2001					
PG-PUB <input type="checkbox"/>		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 110 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no				ATTORNEY DOCKET NO PAS202A	
Verified and Acknowledged Examiner's initials					
TITLE: Nonlinearity error correcting method and phase angle measuring method for displacement measurement in two-frequency laser interferometer and displacement measurement system using					

NOTICE OF ALLOWANCE MAILED		Assistant Examiner		CLAIMS ALLOWED	
				Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner		DRAWING	
Amount Due	Date Paid			Sheets Drwg.	Figs.Drwg.
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE		Application Examiner	
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